imall

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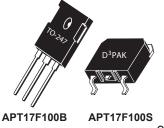


APT17F100B APT17F100S

1000V, 17A, 0.78Ω Max, t_{rr} ≤245ns

N-Channel FREDFET

Power MOS 8TM is a high speed, high voltage N-channel switch-mode power MOSFET. This 'FREDFET' version has a drain-source (body) diode that has been optimized for high reliability in ZVS phase shifted bridge and other circuits through reduced t_{rr} , soft recovery, and high recovery dv/dt capability. Low gate charge, high gain, and a greatly reduced ratio of C_{rss}/C_{iss} result in excellent noise immunity and low switching loss. The intrinsic gate resistance and capacitance of the poly-silicon gate structure help control di/dt during switching, resulting in low EMI and reliable paralleling, even when switching at very high frequency.



Single die FREDFET



FEATURES

- Fast switching with low EMI
- Low t_{rr} for high reliability
- Ultra low C_{rss} for improved noise immunity
- Low gate charge
- Avalanche energy rated
- RoHS compliant

TYPICAL APPLICATIONS

- ZVS phase shifted and other full bridge
- Half bridge
- PFC and other boost converter
- Buck converter
- Single and two switch forward
- Flyback

Absolute Maximum Ratings

Symbol	Parameter	Ratings	Unit
1	Continuous Drain Current @ T _C = 25°C	17	
'D	Continuous Drain Current @ T _C = 100°C	11	A
I _{DM}	Pulsed Drain Current ^①	70	
V_{GS}	Gate-Source Voltage	±30	V
E _{AS}	Single Pulse Avalanche Energy	1070	mJ
I _{AR}	Avalanche Current, Repetitive or Non-Repetitive	9	А

Thermal and Mechanical Characteristics

Symbol	Characteristic	Min	Тур	Мах	Unit	
P _D	Total Power Dissipation @ $T_{C} = 25^{\circ}C$			625	W	
R _{θJC}	Junction to Case Thermal Resistance			0.20	20 °C/W	
R _{ecs}	Case to Sink Thermal Resistance, Flat, Greased Surface		0.11			
T_,T _{STG}	Operating and Storage Junction Temperature Range	-55		150	°C	
TL	Soldering Temperature for 10 Seconds (1.6mm from case)			300		
W _T	Package Weight		0.22		ΟZ	
чт			5.9		g	
Torque	Mounting Torque (TO-247 Package), 6-32 or M3 screw			10	in∙lbf	
				1.1	N∙m	

Static Characteristics

T_J = 25°C unless otherwise specified

APT17F100B S

Symbol	Parameter	Test Conditions		Min	Тур	Мах	Unit
V _{BR(DSS)}	Drain-Source Breakdown Voltage	$V_{GS} = 0V, I_{D} = 250 \mu A$		1000			V
$\Delta V_{BR(DSS)} / \Delta T_J$	Breakdown Voltage Temperature Coefficient	Reference to 25°C, I _D = 250µA			1.15		V/°C
R _{DS(on)}	Drain-Source On Resistance ^③	V _{GS} = 10V, I _D = 9A			0.67	0.78	Ω
V _{GS(th)}	Gate-Source Threshold Voltage	$V_{GS} = V_{DS}, I_{D} = 1mA$		2.5	4	5	V
$\Delta V_{GS(th)} / \Delta T_J$	Threshold Voltage Temperature Coefficient				-10		mV/°C
	Zero Gate Voltage Drain Current	V _{DS} = 1000V	T _J = 25°C			250	μA
DSS		V _{GS} = 0V	T _J = 125°C			1000	
I _{GSS}	Gate-Source Leakage Current	$V_{GS} = \pm 30V$				±100	nA

Dynamic Characteristics

T_J = 25°C unless otherwise specified

Symbol	Parameter	Test Conditions	Min	Тур	Мах	Unit
9 _{fs}	Forward Transconductance	V _{DS} = 50V, I _D = 9A		19		S
C _{iss}	Input Capacitance			4845		
C _{rss}	Reverse Transfer Capacitance	$V_{GS} = 0V, V_{DS} = 25V$ f = 1MHz		65		
C _{oss}	Output Capacitance	1 111112		405		
C _{o(cr)} ④	Effective Output Capacitance, Charge Related			165		pF
C _{o(er)} (5)	Effective Output Capacitance, Energy Related	$V_{GS} = 0V, V_{DS} = 0V \text{ to } 667V$		85		
Q _g	Total Gate Charge			150		
Q _{gs}	Gate-Source Charge	$V_{GS} = 0 \text{ to } 10V, I_D = 9A,$ $V_{DS} = 500V$		26		nC
Q _{gd}	Gate-Drain Charge	v _{DS} = 500V		70		
t _{d(on)}	Turn-On Delay Time	Resistive Switching		29		
t _r	Current Rise Time	V _{DD} = 667V, I _D = 9A		31		ns
t _{d(off)}	Turn-Off Delay Time	$R_{G}^{}$ = 4.70 $^{\odot}$, $V_{GG}^{}$ = 15V		105		115
t _f	Current Fall Time			28		

Source-Drain Diode Characteristics

Symbol	Parameter	Test Conditions	Min	Тур	Мах	Unit
۱ _s	Continuous Source Current (Body Diode)	MOSFET symbol showing the			17	А
I _{SM}	Pulsed Source Current (Body Diode) ^①	integral reverse p-n junction diode (body diode)	l s		65	
V _{SD}	Diode Forward Voltage	I _{SD} = 9A, T _J = 25°C, V _{GS} = 0V			1.0	V
t _{rr}		T _J = 25°C		215	245	20
۲r	Reverse Recovery Time	T _J = 125°C		385	465	ns
Q _{rr}	Reverse Recovery Charge	$I_{SD} = 9A^{(3)}$ $T_J = 25^{\circ}C$		1.02		
α _{rr}		$di_{SD}/dt = 100A/\mu s$ $T_J = 125^{\circ}C$		2.57		μC
1	Reverse Recovery Current	$V_{DD} = 100V$ $T_{J} = 25^{\circ}C$		9.03		٨
'rrm		T _J = 125°C		12.83		A
dv/dt	Peak Recovery dv/dt	$I_{SD} \le 9A$, di/dt $\le 1000A/\mu s$, $V_{DD} = 400V$, $T_J = 125^{\circ}C$,		25	V/ns

(1) Repetitive Rating: Pulse width and case temperature limited by maximum junction temperature.

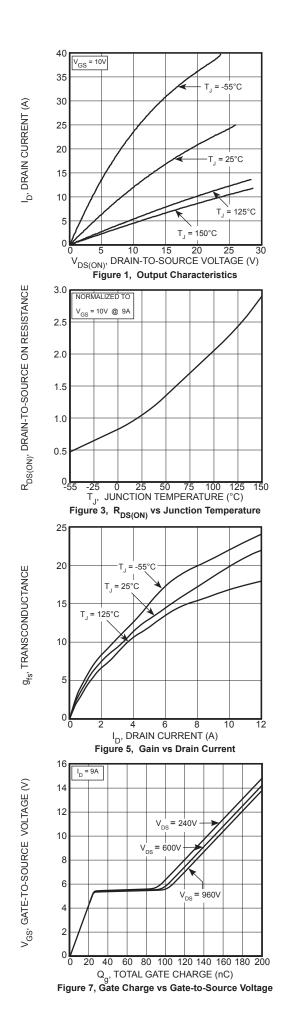
(2) Starting at $T_J = 25^{\circ}C$, L = 26.42mH, $R_G = 25\Omega$, $I_{AS} = 9A$.

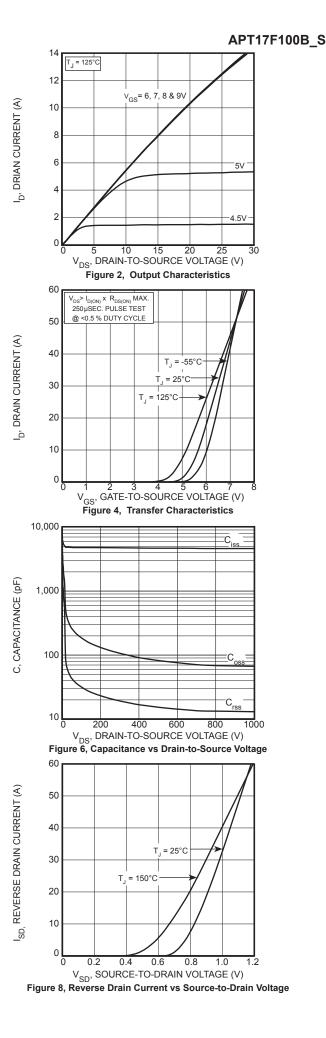
(3) Pulse test: Pulse Width < 380μ s, duty cycle < 2%.

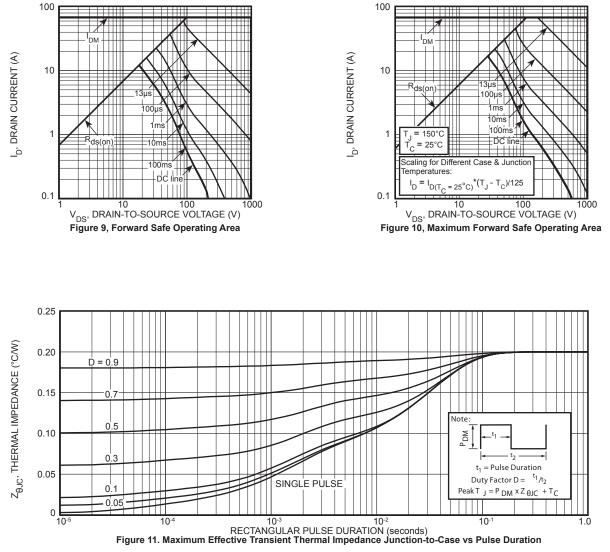
(4) C_{o(cr)} is defined as a fixed capacitance with the same stored charge as C_{OSS} with V_{DS} = 67% of V_{(BR)DSS}.
(5) C_{o(er)} is defined as a fixed capacitance with the same stored energy as C_{OSS} with V_{DS} = 67% of V_{(BR)DSS}. To calculate C_{o(er)} for any value of V_{DS} less than V_{(BR)DSS}, use this equation: C_{o(er)} = -1.41E-8/V_{DS}² + 2.48E-9/V_{DS} + 4.81E-11.

6 R_G is external gate resistance, not including internal gate resistance or gate driver impedance. (MIC4452)

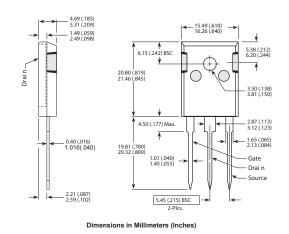
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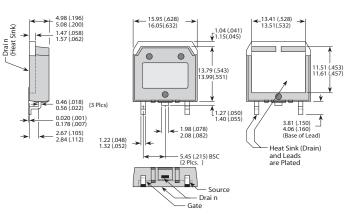




TO-247 (B) Package Outline (e1) SAC: Tin, Silver, Copper



D³PAK Package Outline © 100% Sn Plated



Dimensions in Millimeters (Inches)